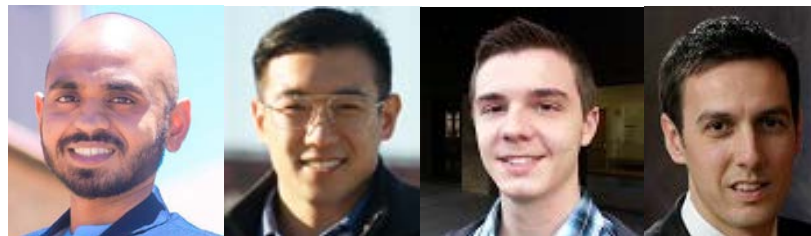


NEEDS Workshop at Stanford: June 21, 2017

2D Materials and Graphene: Science to Nanofunctions

Saurabh Suryavanshi & Eric Pop
Stanford University



Experimental collaborators: Ning Wang, Kirby Smithe (Pop group)
Industry collaboration: ARM, Lam, Northrop Grumman + CEA LETI



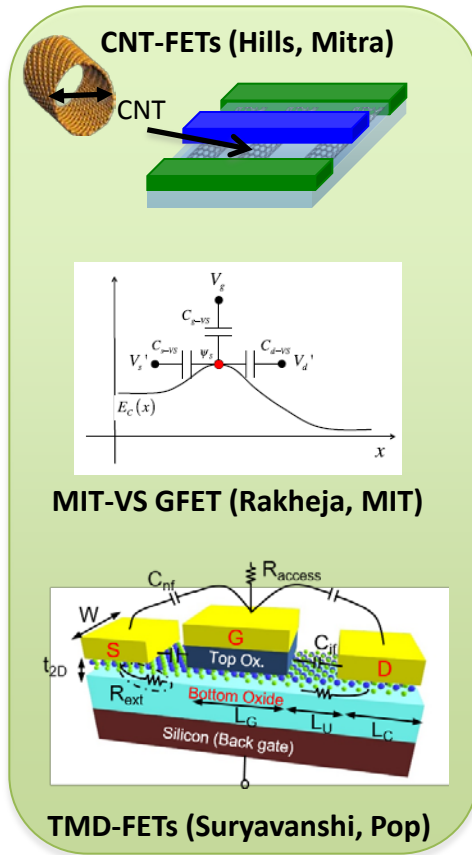
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Introduction

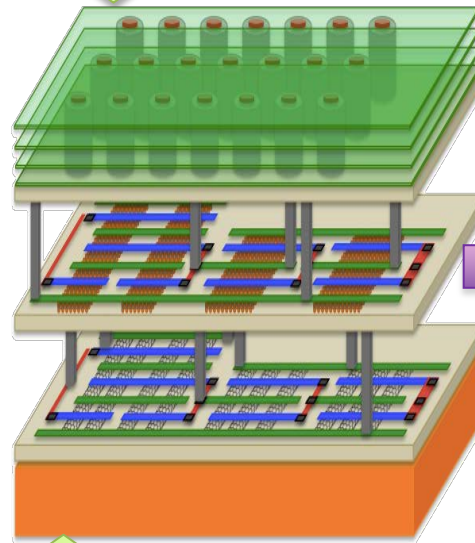
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Compact device models do not exist by themselves but as part of a system

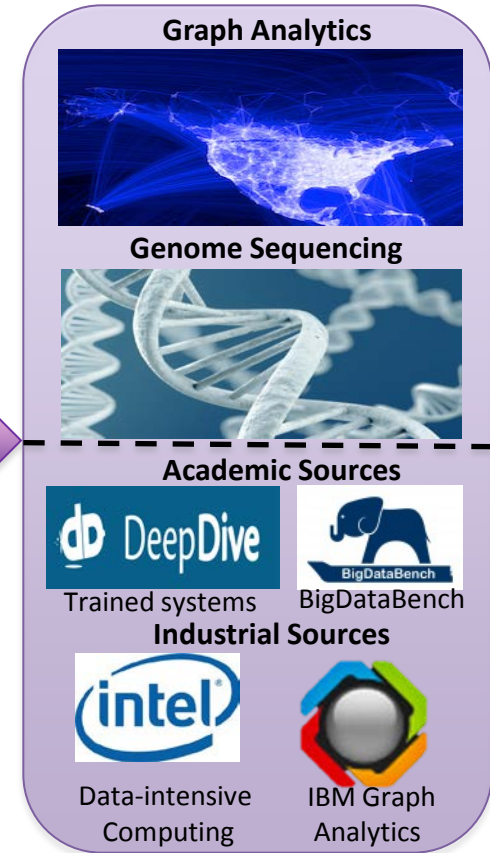
Emerging Technologies



Compact & System Models



Monolithic 3D Integration of Electronics



Abundant-Data Applications



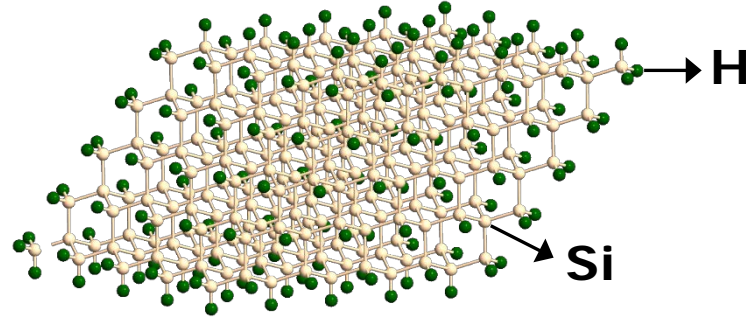
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2D materials or Layered materials

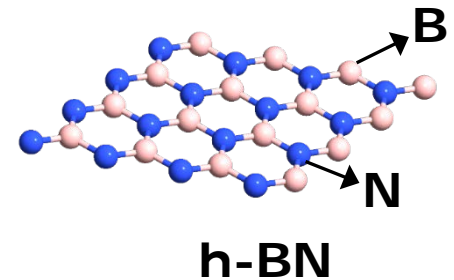
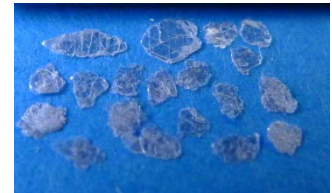
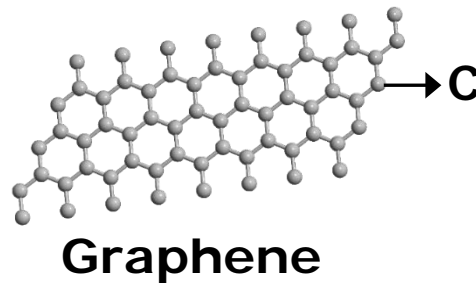
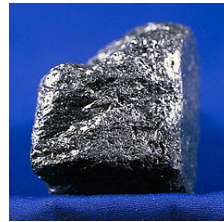
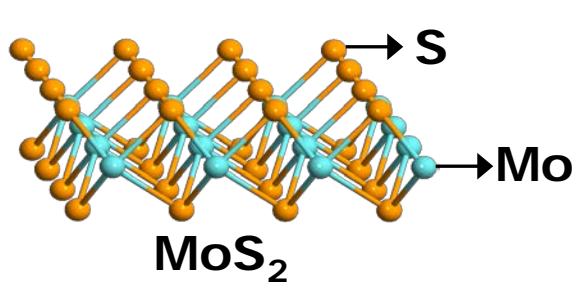


Silicon



Crystal images taken from Wikipedia.org

- Atomically thin, no surface dangling bond



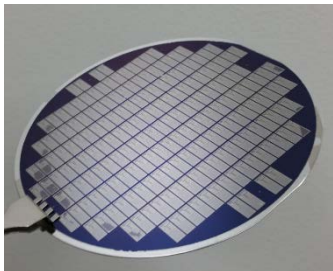
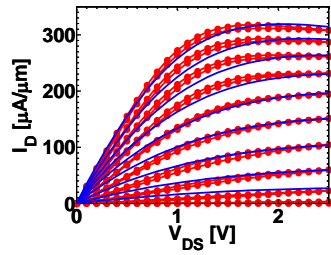
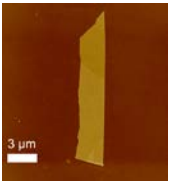
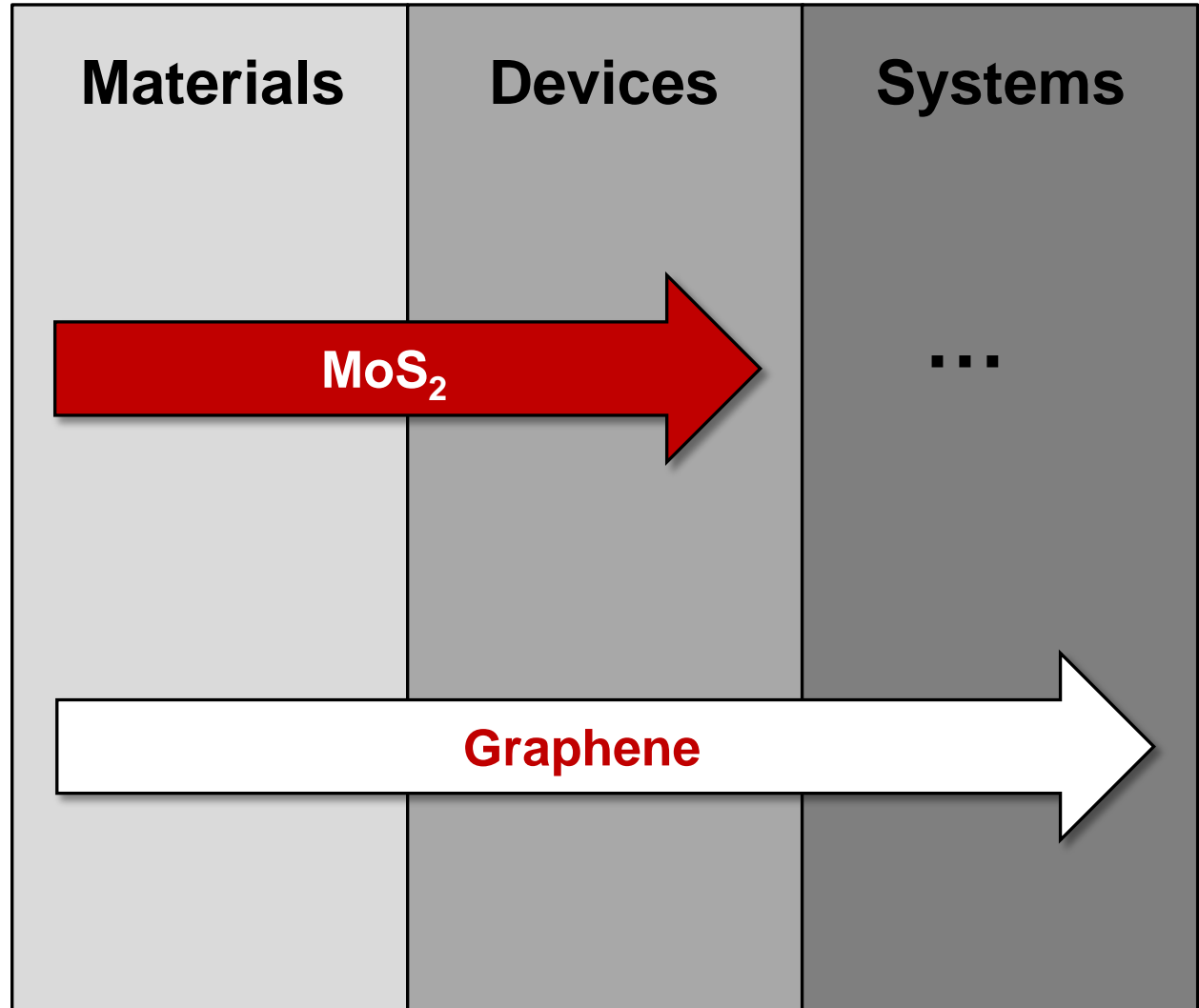
- Semiconducting(MoS₂), Semimetallic (graphene), Insulating(BN)₃



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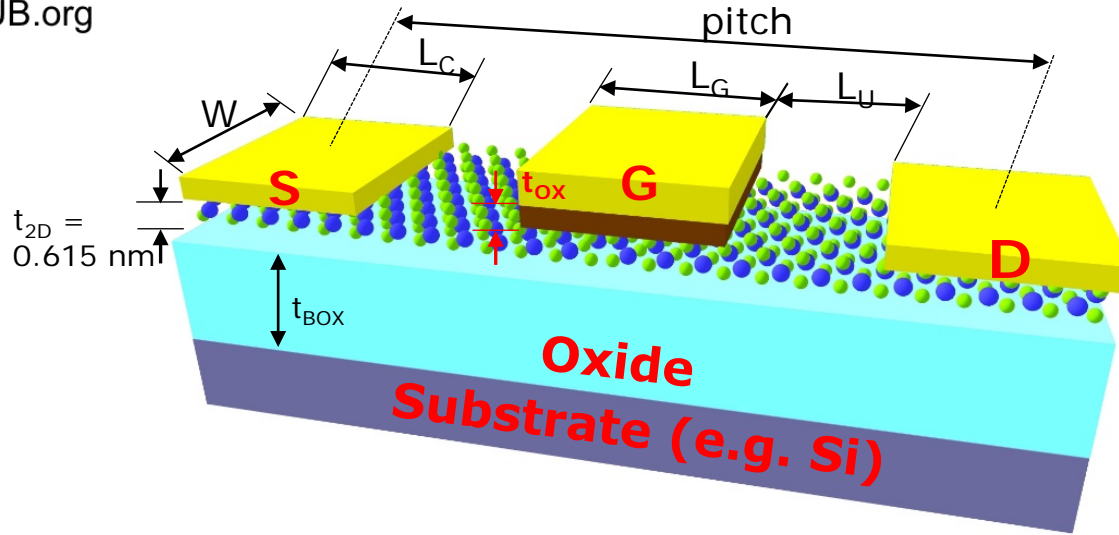
2D Materials to Systems (Today)



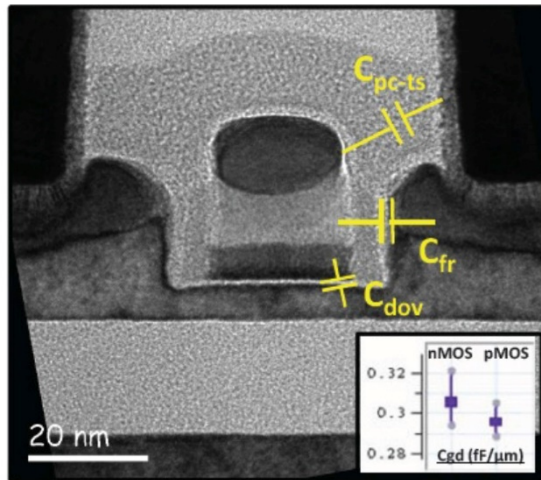


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NEEDS 2D Field Effect Transistors

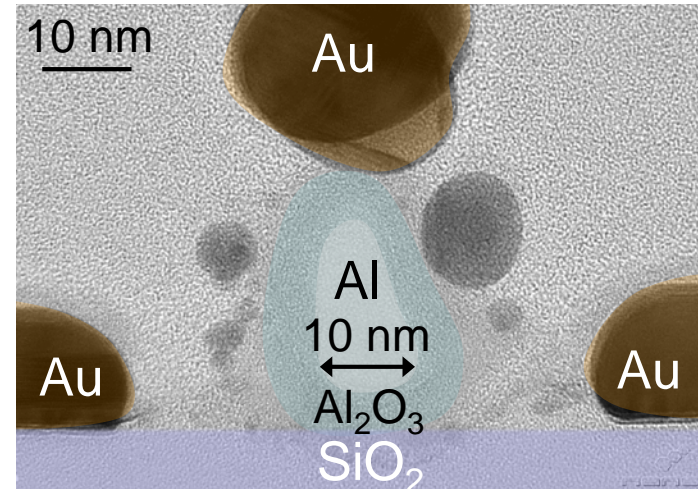


“14 nm” FD SOIFET



(O. Weber et al., VLSI Technology, 2014)[LETI, IBM]

“14 nm” MoS₂ on oxide FET



(C. D. English; E. Pop et. al, IEDM, 2016) [Stanford]



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S2DS: Physics-Based Compact Model

needs.nanoHUB.org S. V. Suryavanshi and E. Pop, *J. Applied Phys.* **120**, 224503 (2016)



<https://nanohub.org/publications/18>

Stanford 2D Semiconductor (S2DS)
Transistor Model 1.1.0

→ Download Bundle

[Additional materials available](#)

Version 1.1.0 - published on 04 Apr 2016

doi:10.4231/D3ZC7RV9X - [cite this](#)

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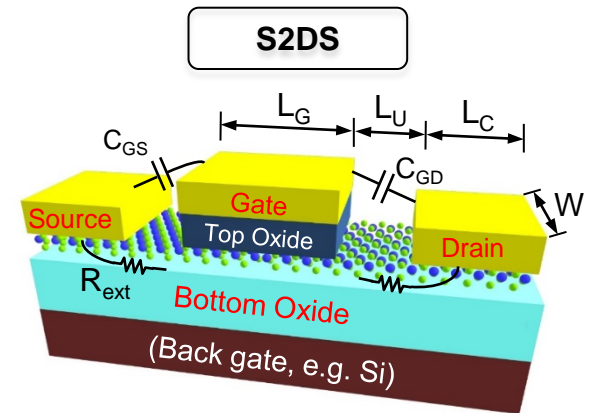
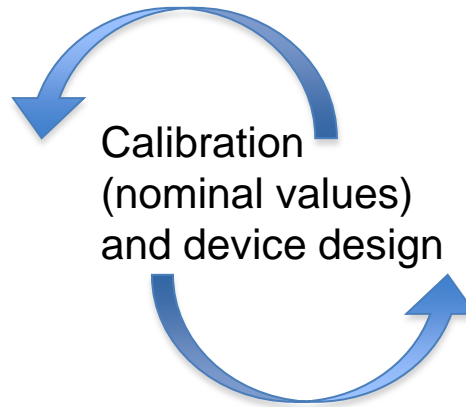
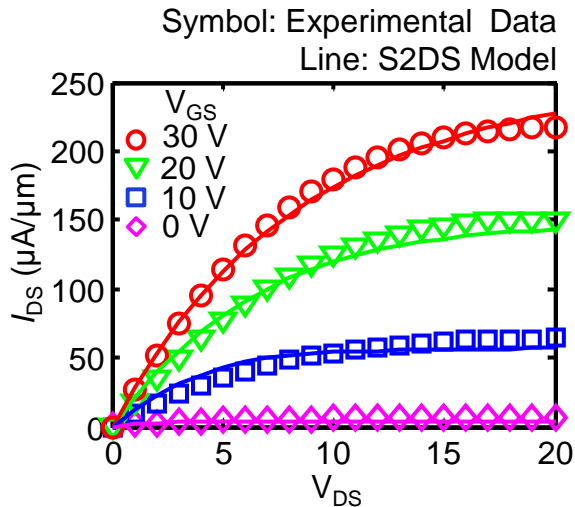
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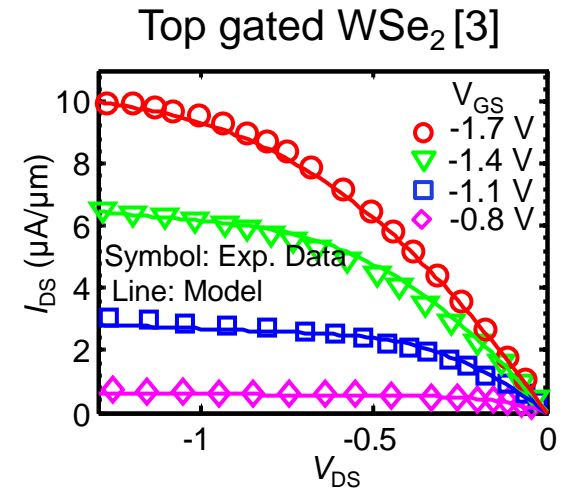
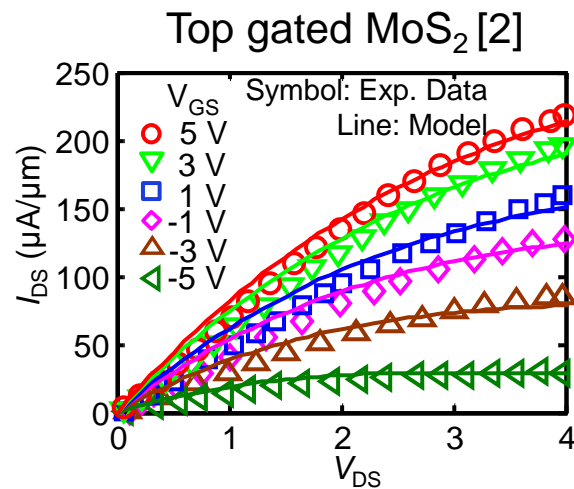
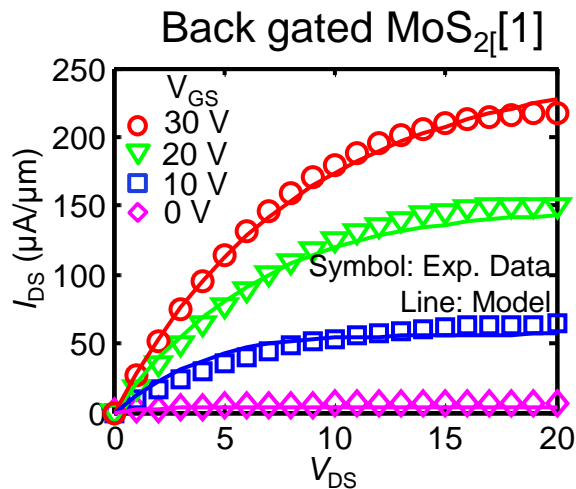




NEEDS S2DS: Physics-Based Compact Model

needs.nanoHUB.org S. V. Suryavanshi and E. Pop, *J. Applied Phys.* **120**, 224503 (2016)

- S2DS, key highlights:
 - a) Emphasis on agreement with experimental data
 - b) Simulate sub-100 nm channel lengths
 - c) 2D channel and quantum capacitance
 - d) Mobility: temperature, field, traps and doping
 - e) Self-heating considering anisotropy



[1] Kirby Smithe and Eric Pop, unpublished
[2] A. Sanne et al., *Nano Letters*, 15, 5038-5045 (2015)
[3] H. Fang et al., *Nano Letters*, 12, 3788-3792 (2012)



NEEDS

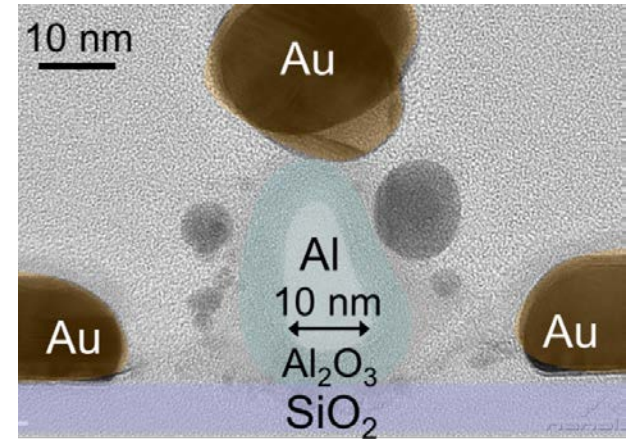
2D for Sub-10 nm: Challenges

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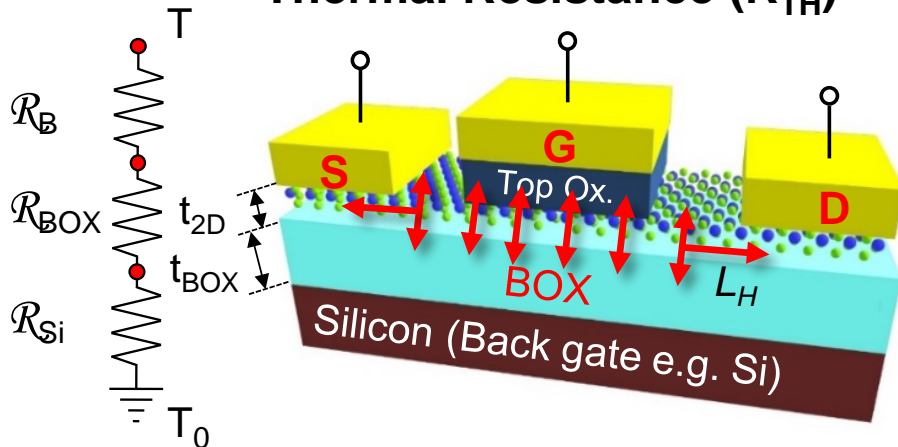
S. V. Suryavanshi and E. Pop (in preparation)

- Importance of scaled devices
- Physical understanding helps to develop better models and guide experimental efforts

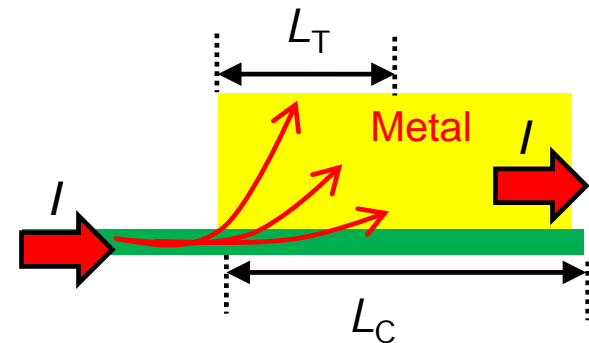
C. English, E. Pop, et al. IEDM (2016)



Thermal Resistance (R_{TH})



Contact Resistance (R_C)





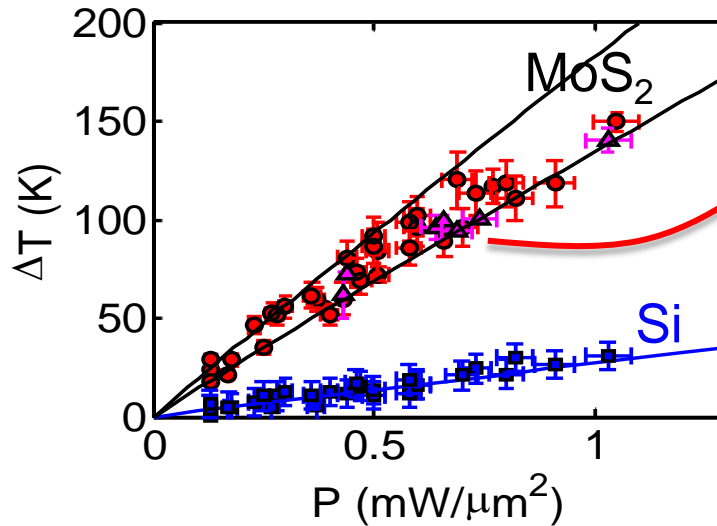
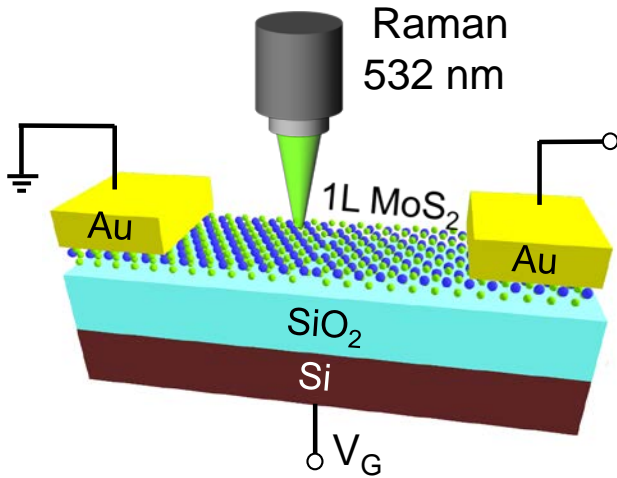
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Self-Heating – Experiment & Models

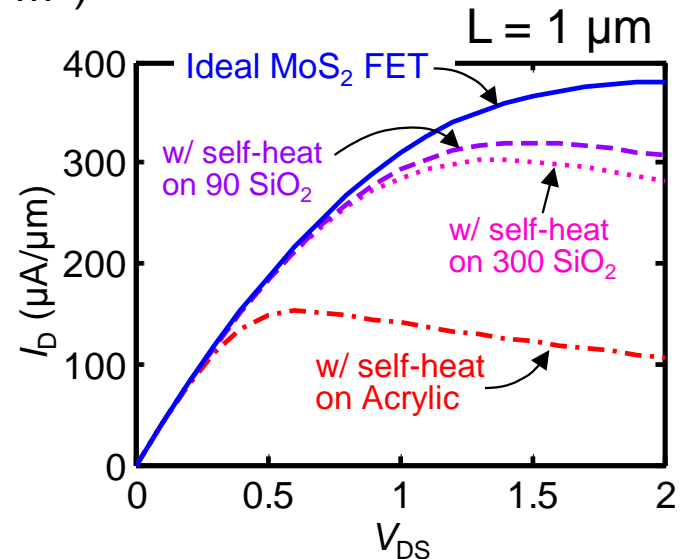
S. V. Suryavanshi and E. Pop, *J. Appl. Phys.* 120, 224503 (2016)

E. Yalon, ..., S.V. Suryavanshi, E. Pop et al., *Nano. Lett.*, 2017



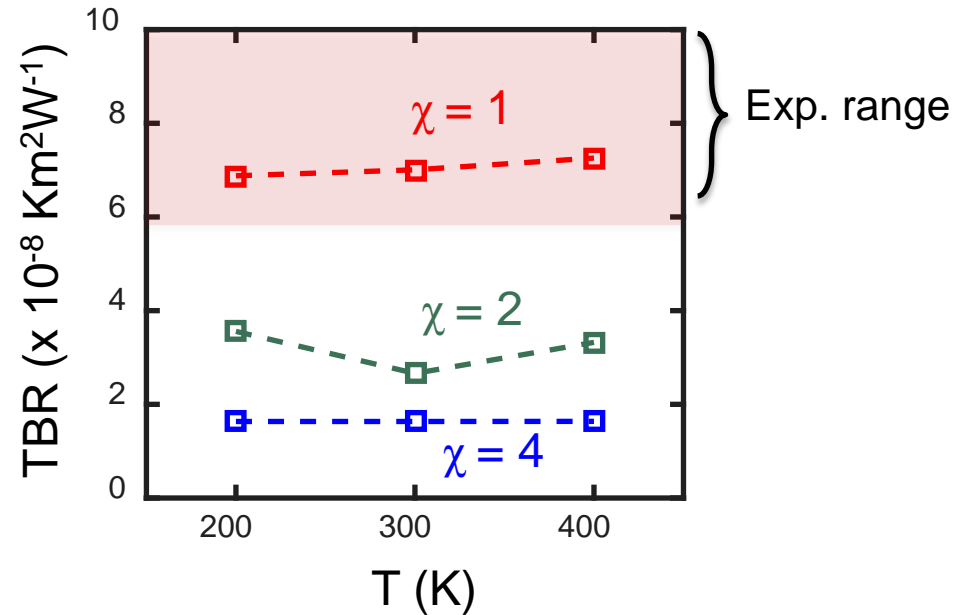
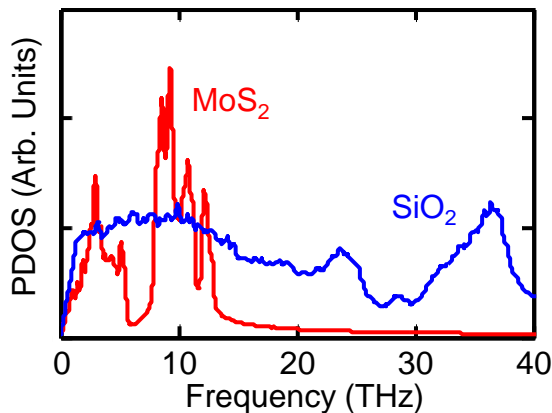
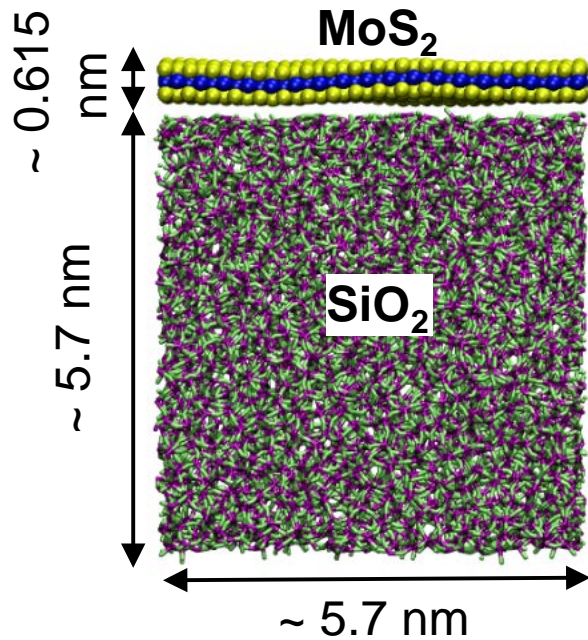
slope gives TBR ~
6 to 10 × 10⁻⁸ Km²/W
(50x higher than Si-SiO₂ TBR)

- Raman thermometry **verifies our thermal models**
- MoS₂-SiO₂ thermal boundary resistance (TBR) accounts for 30% of R_{TH}
- Perfect heat sinking could boost I_D > 20%





Molecular Dynamic (MD) Simulations



- χ is the interaction strength between MoS₂ and SiO₂
- Increasing χ or making the interface cleaner could decrease the TBR

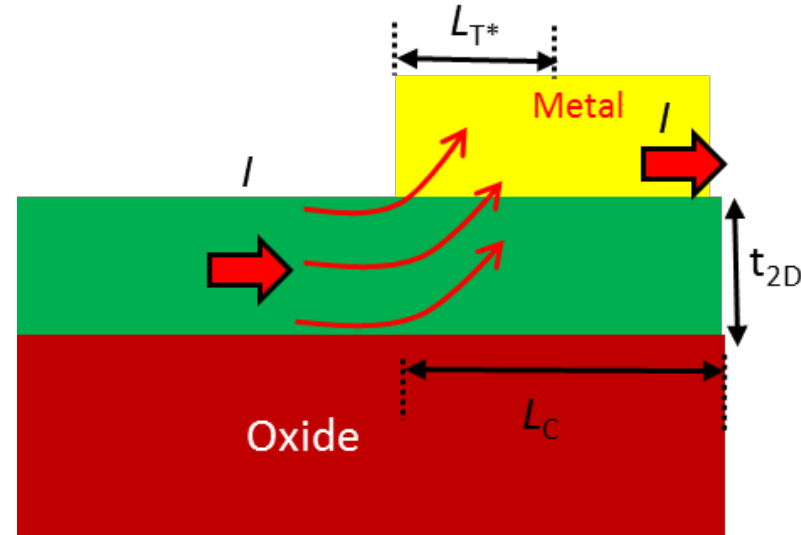


Contact Resistance – Crowding

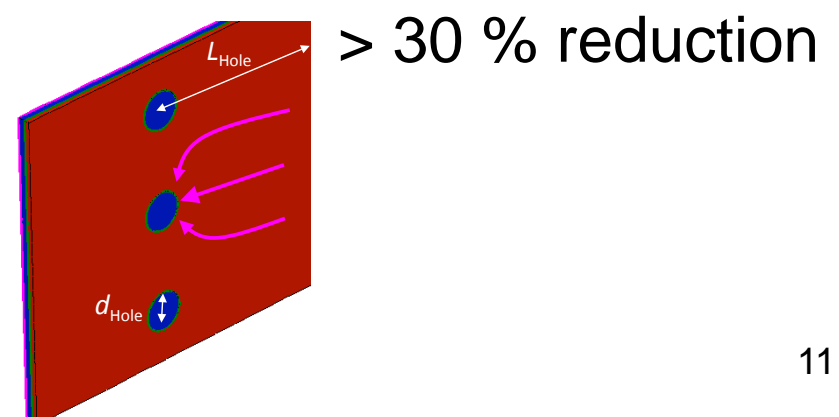
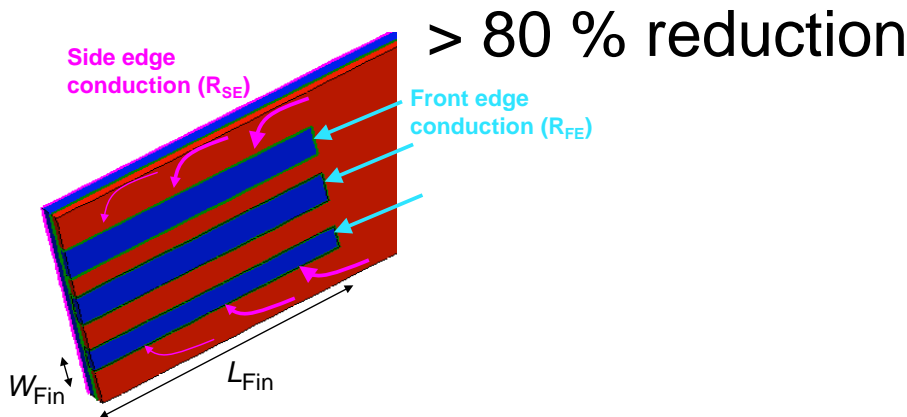
S. V. Suryavanshi and E. Pop (in preparation)

Significant current crowding...

- Material property ($\propto \mu_{in}/\mu_{out}$)
- Contact geometry ($\propto t_{2D}/L_T$)
- Contact depletion ($\propto \exp(\phi_B)/t_{2D}$)
- Intrinsic contact resistivity



✓ Current crowding can be reduced by contact patterning

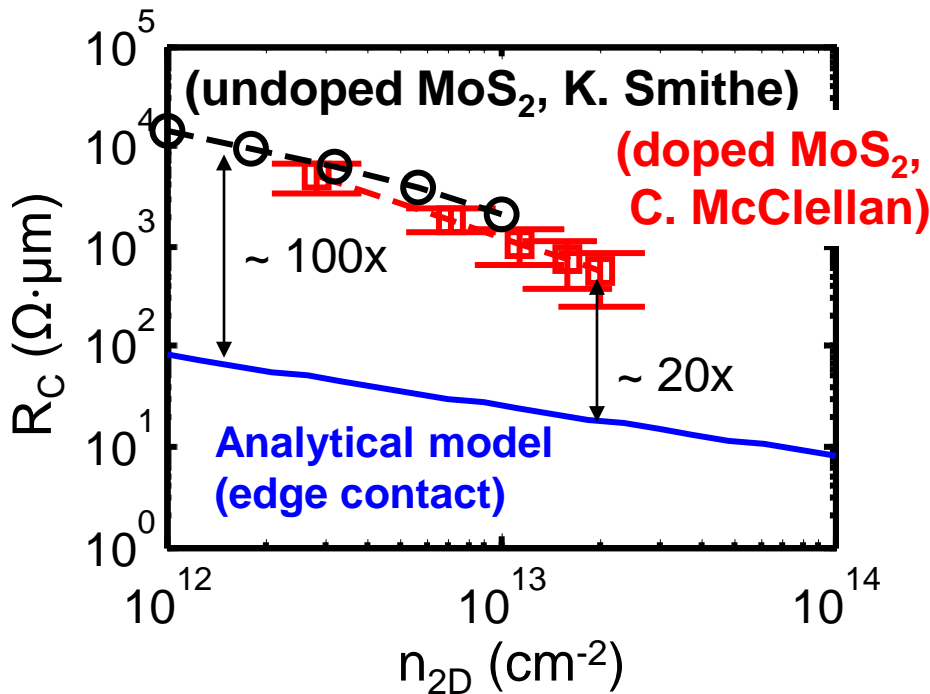




Contact Resistance – Intrinsic Limit

S. V. Suryavanshi and E. Pop (in preparation)

C. McClellan, ..., S.V. Suryavanshi, E. Pop, DRC, 2017



- Landauer model (J. Maassen et al., APL, 2013)

- Assumptions:

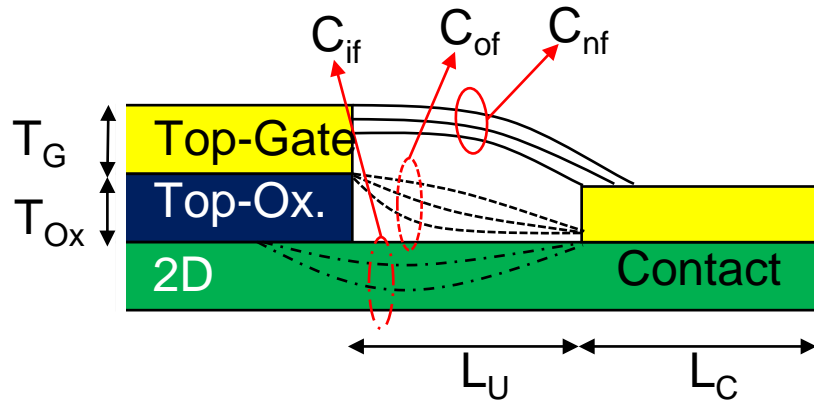
- Single parabolic band structure
- $T = 0$ K

$$\frac{1}{\rho_C^{LL}} = \frac{4q^2}{h} \int_{-\infty}^{\infty} M(\varepsilon)T(\varepsilon) \left[-\frac{df}{d\varepsilon} \right] d\varepsilon$$

- ✓ Large carrier density increases the number of modes
- ✓ Doping reduces the transmission
- ✓ Making cleaner interface (C. English, E. Pop et al., *Nano Lett.*, 2016)

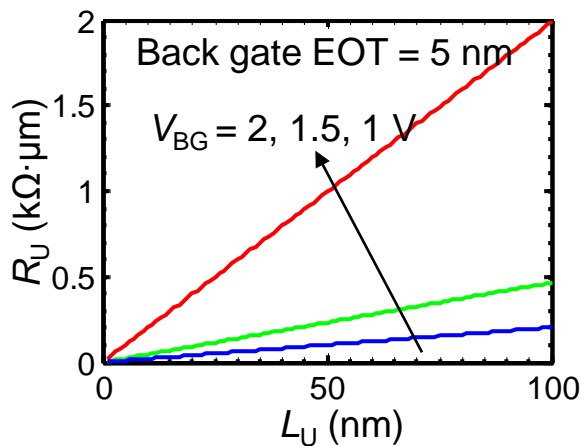
Device Optimization, Design and Benchmarking

S. V. Suryavanshi and E. Pop, *J. Applied Phys.* **120**, 224503 (2016)

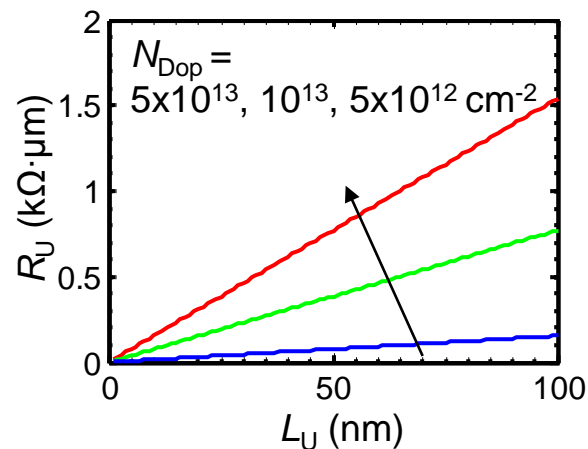


S2DS includes analytical forms for fringe capacitances and external resistances

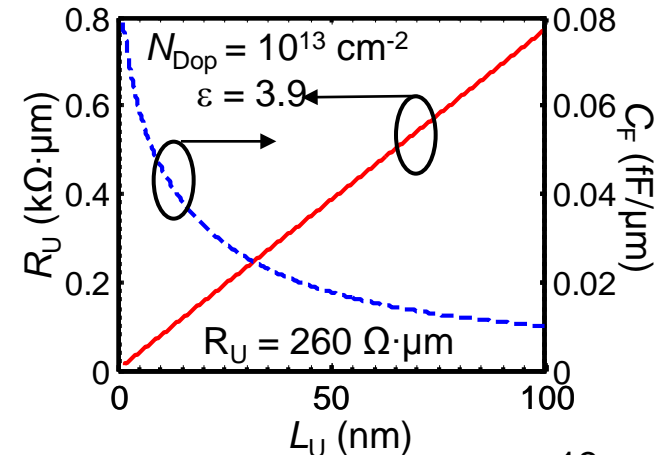
Back-gate



Charge-transfer Doping



Optimization



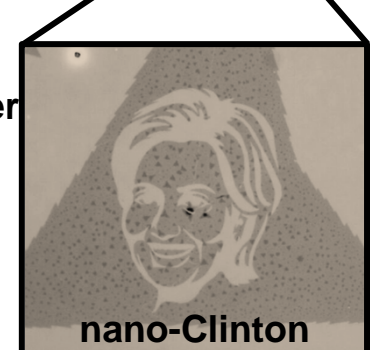
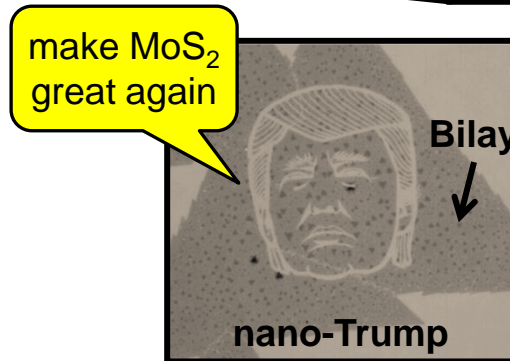
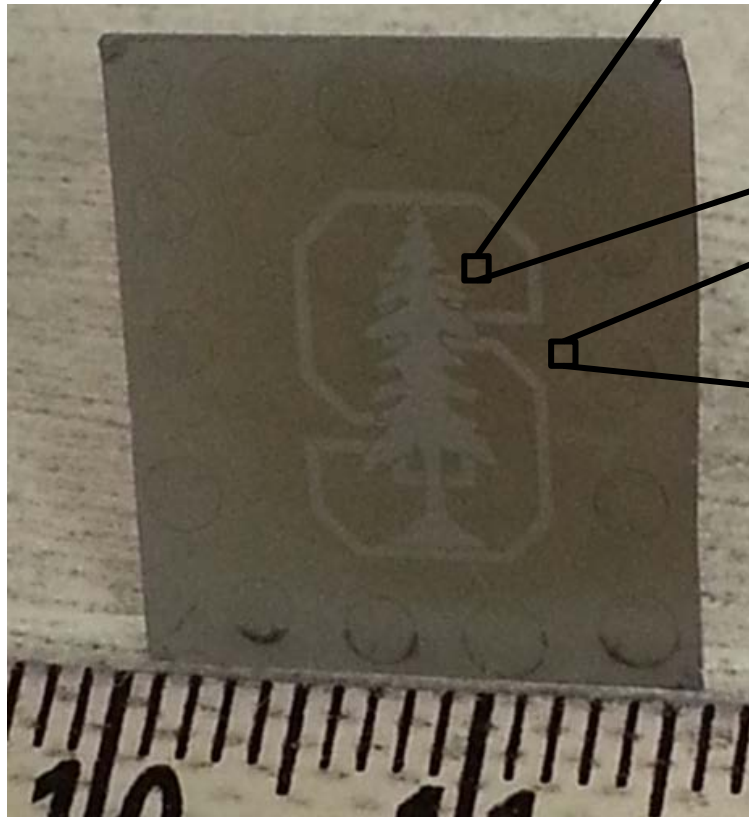
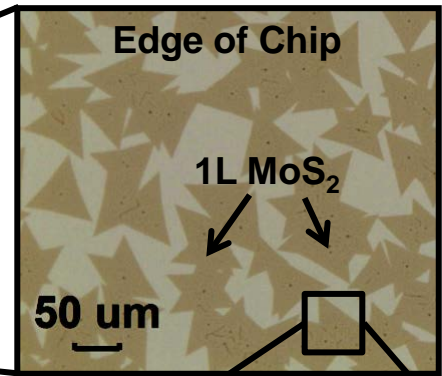
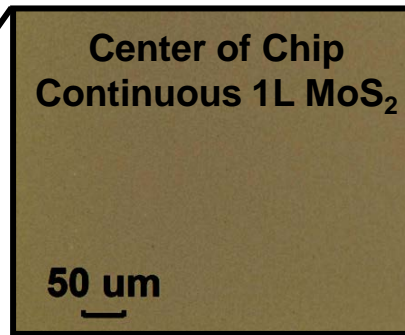
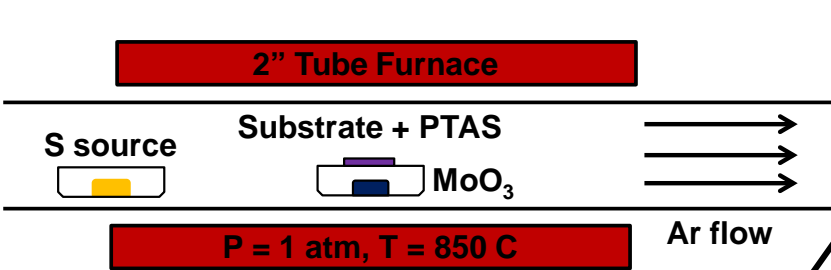


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Large-Area MoS₂ Grown by CVD

K.K.H. Smithe, C. D. English, S. V. Suryavanshi, and E. Pop, *2D Mater.* 4 0110009 (2017).



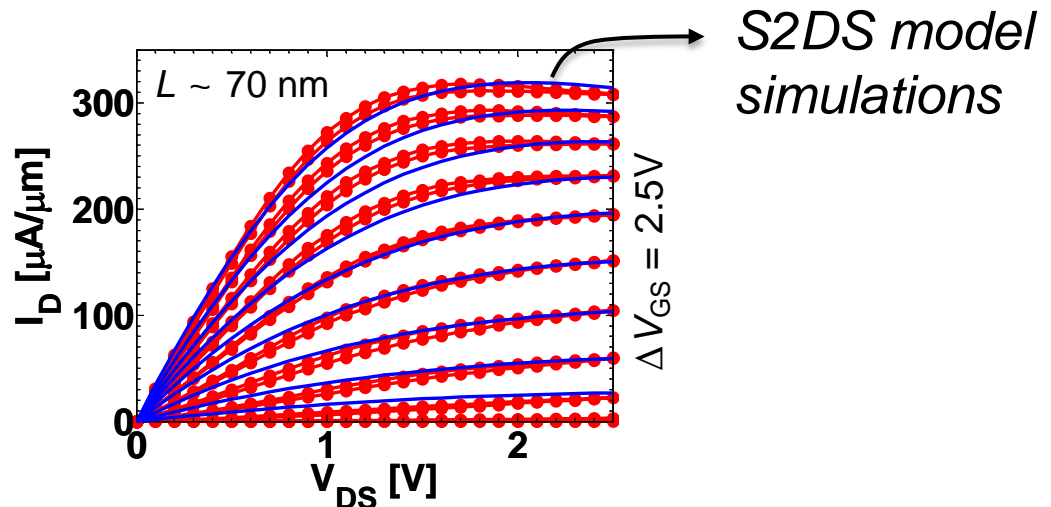
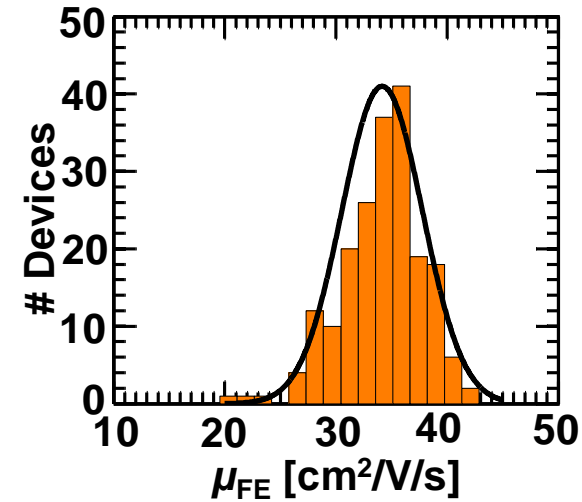
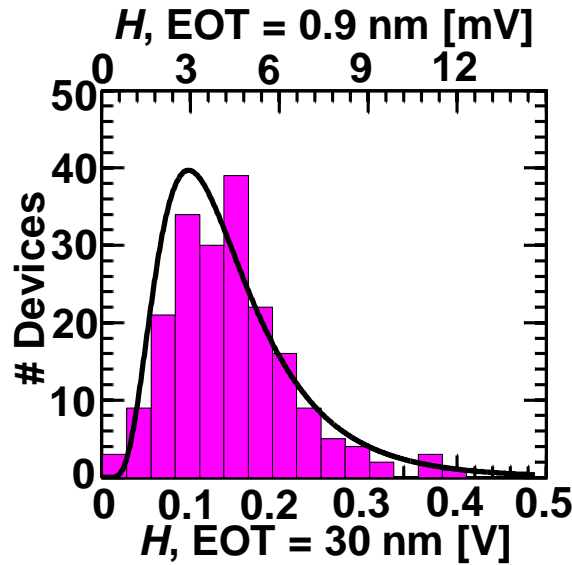
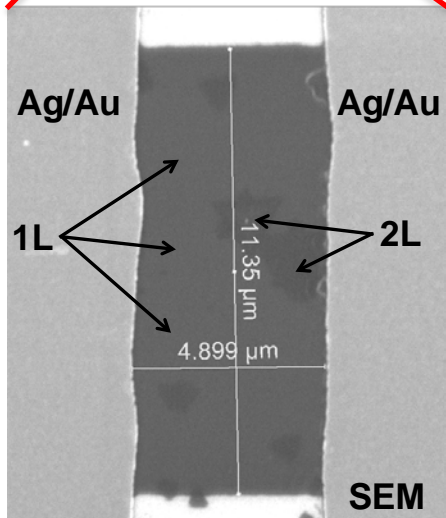
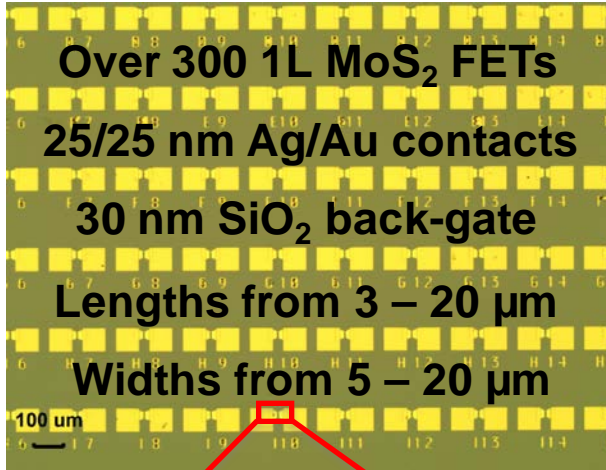


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Scaling Up MoS₂ - 100s of devices

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K.K.H. Smithe, S. V. Suryavanshi, E. Pop et al., in review, 2017





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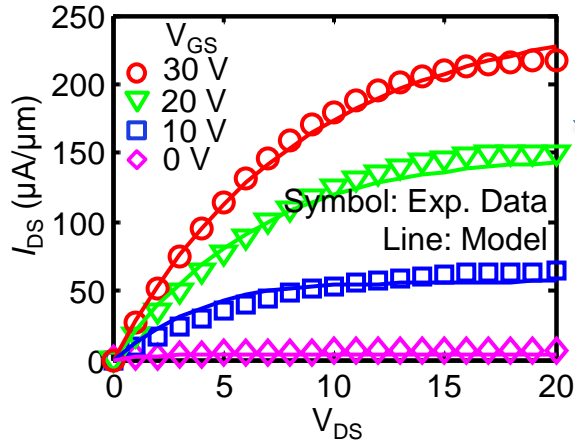
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Modeling Variability in 2D Nanofabrics

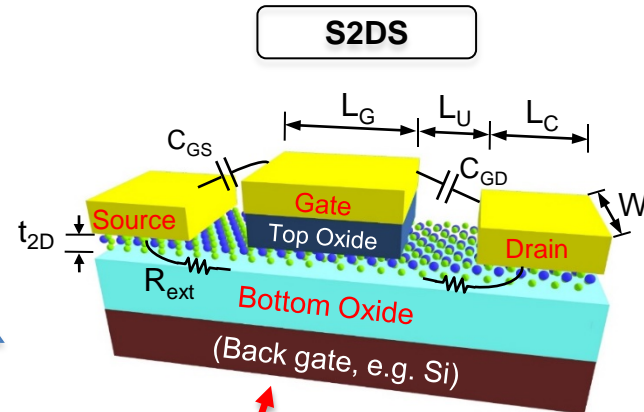
S. V. Suryavanshi and E. Pop, *J. Applied Phys.* **120**, 224503 (2016)

K.K.H. Smithe, S. V. Suryavanshi, E. Pop et al., in review, 2017

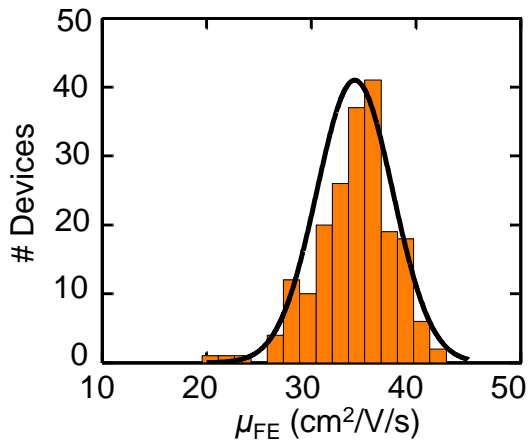
Device data



Calibration (nominal values) and device design



Variability



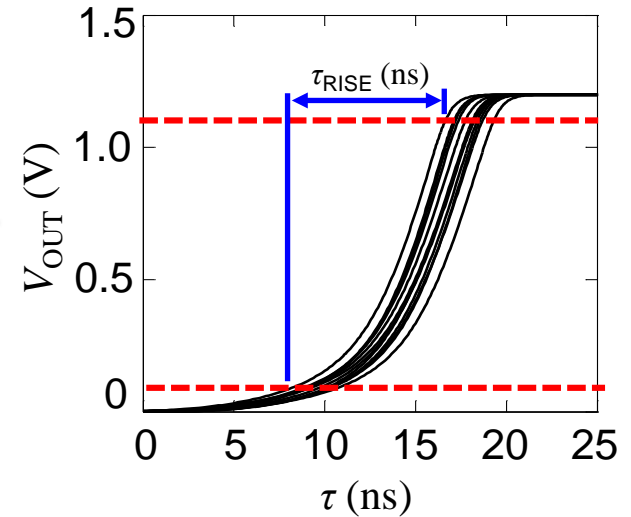
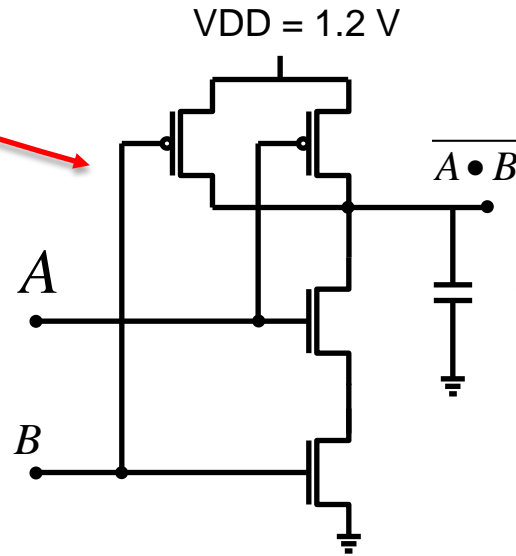
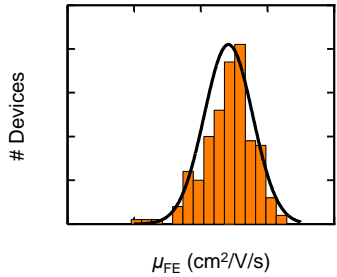
Variation model (***New***) (Coefficient of variation, CV)

- R_C
- v_{sat}
- μ_{eff}
- n_{IMP}, V_T
- (x_i, y_i, z_i)
- \vdots

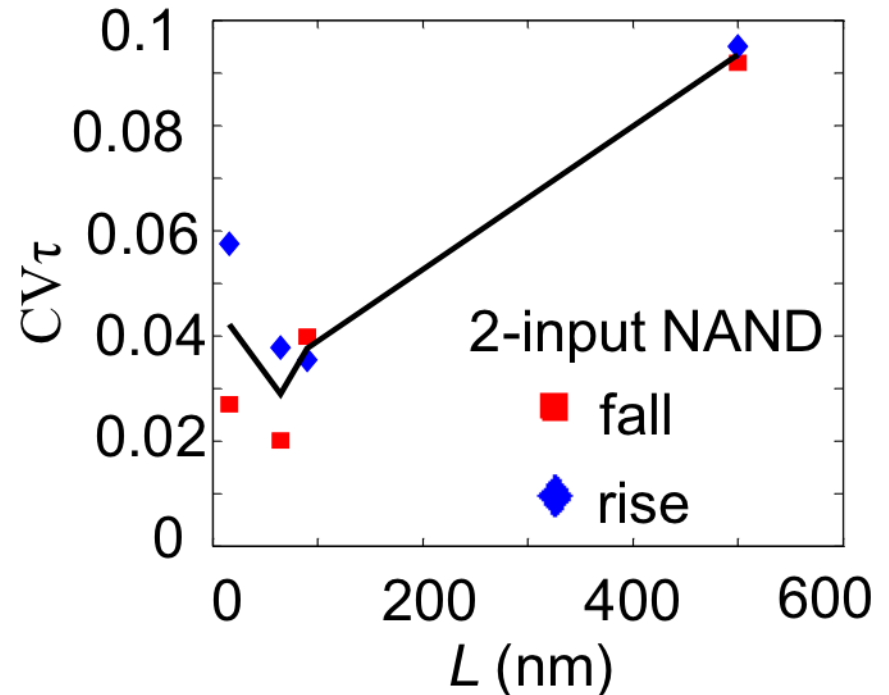
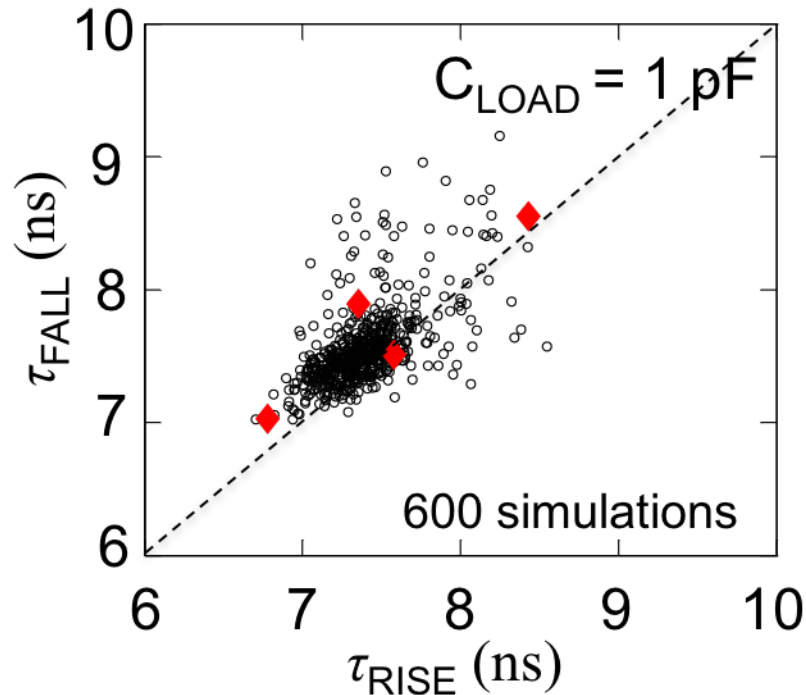


Monte Carlo Engine

2-input NAND gate
(65 nm technology)



- Monte Carlo simulations to assess the effective variability in nanofunctions
- Can be extended to any circuits and systems

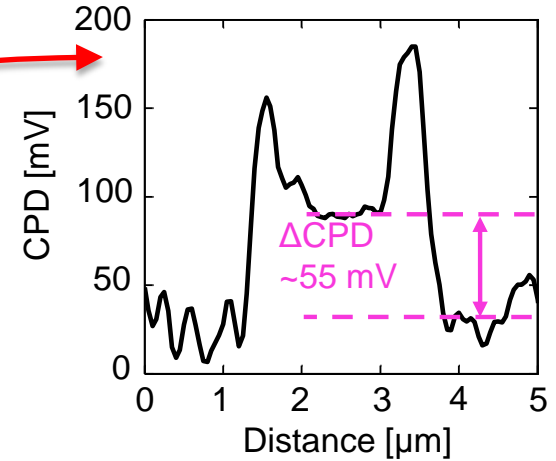
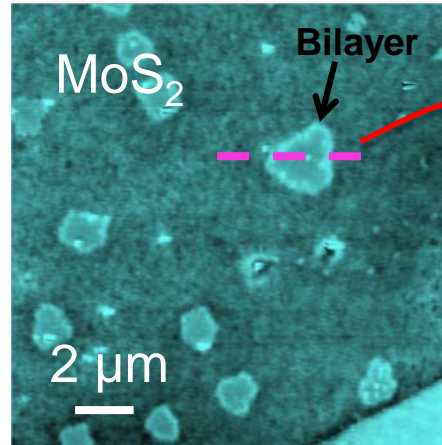
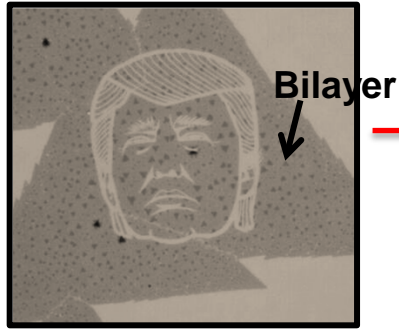


- Bi-layer islands do not cause significant variation for n-type devices
- We can do similar Monte Carlo calculations for nanofunction *energy*
- **Future work:** how does variation affect the EDP in large circuits?



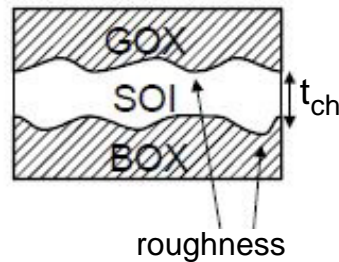
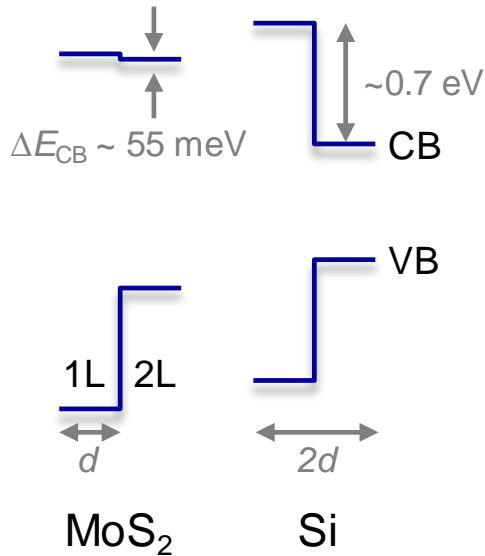
Variability in 2D Nanofabrics

K.K.H. Smithe, S. V. Suryavanshi, E. Pop et al., in review, 2017



(*CPD – contact potential difference)

(SKPM: Miguel Minoz)



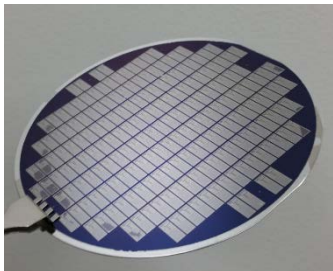
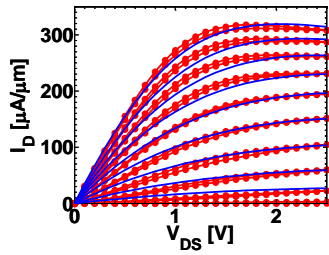
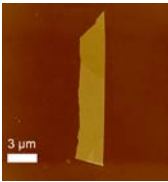
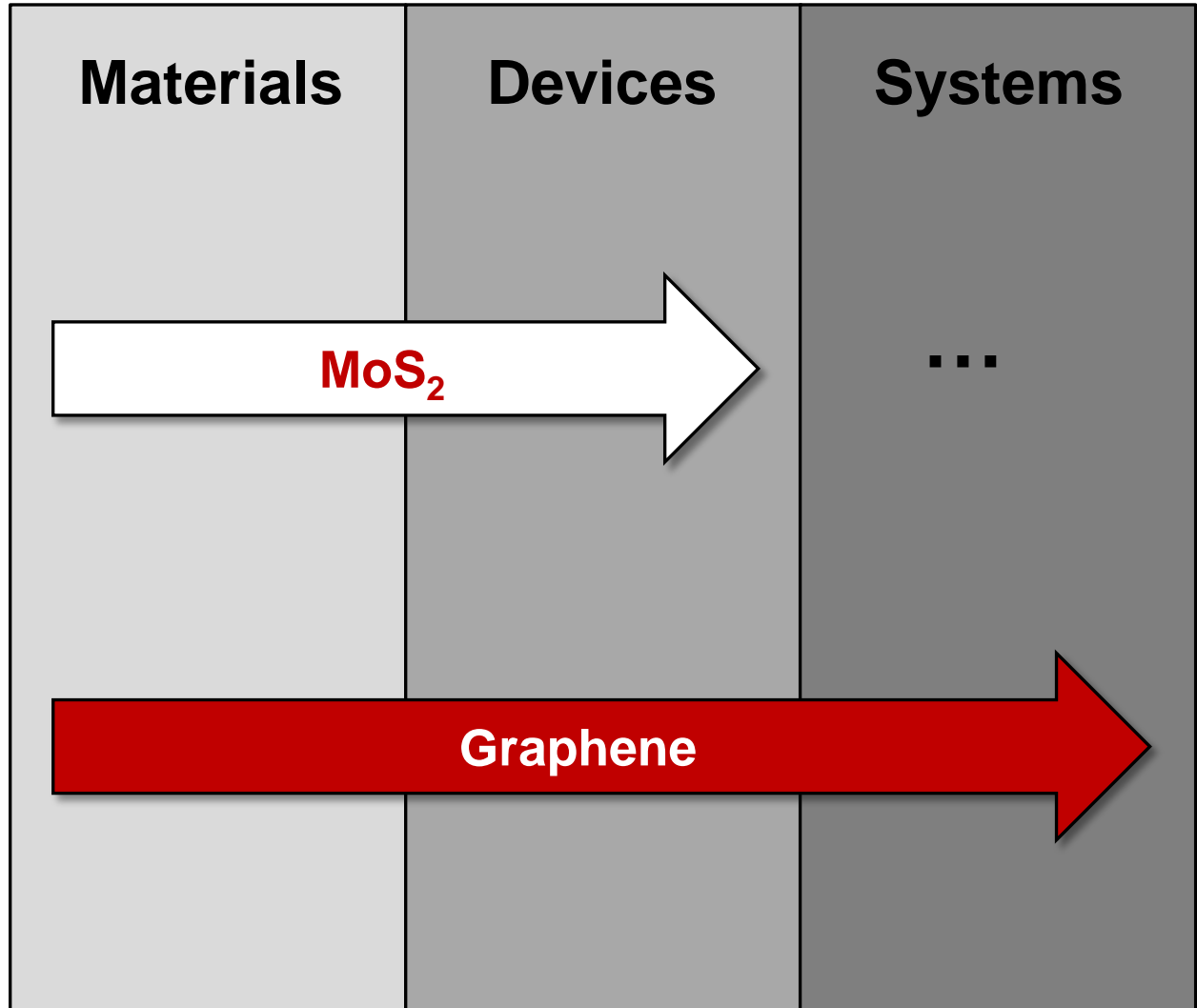
- Less variation in V_T due to smaller band offset in conduction band (CB)
- Silicon, for similar thickness variation, will have >10x larger CB variation



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2D Materials to Systems (Today)

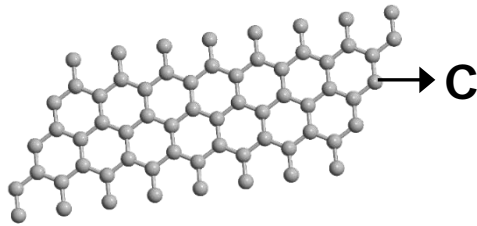
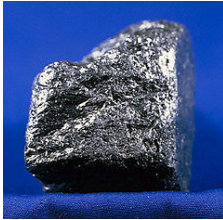




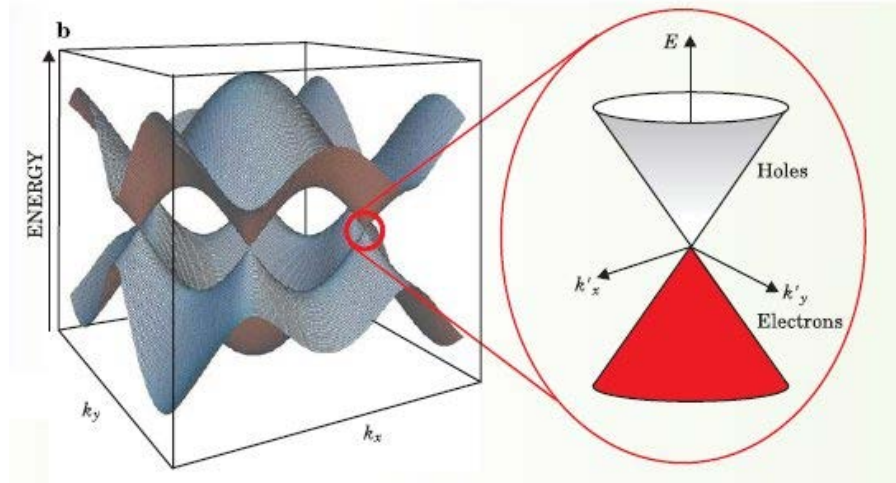
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Graphene - Introduction

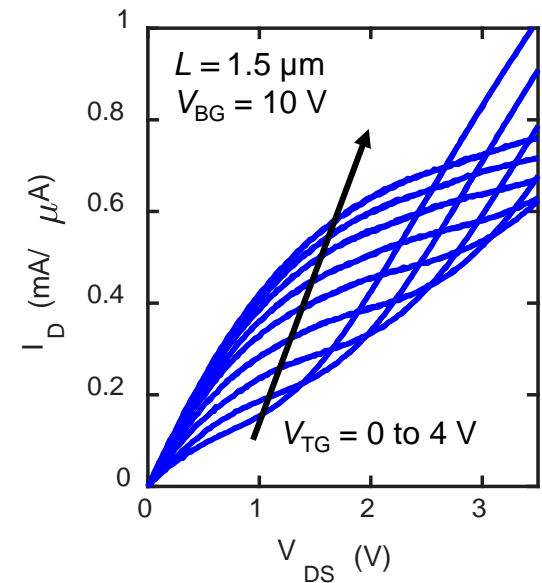
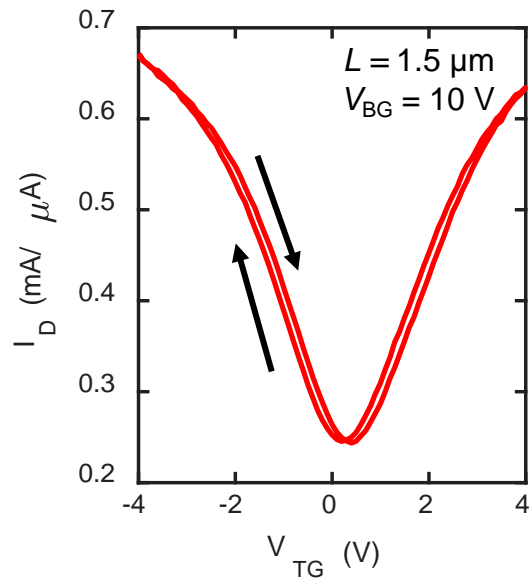
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Graphene



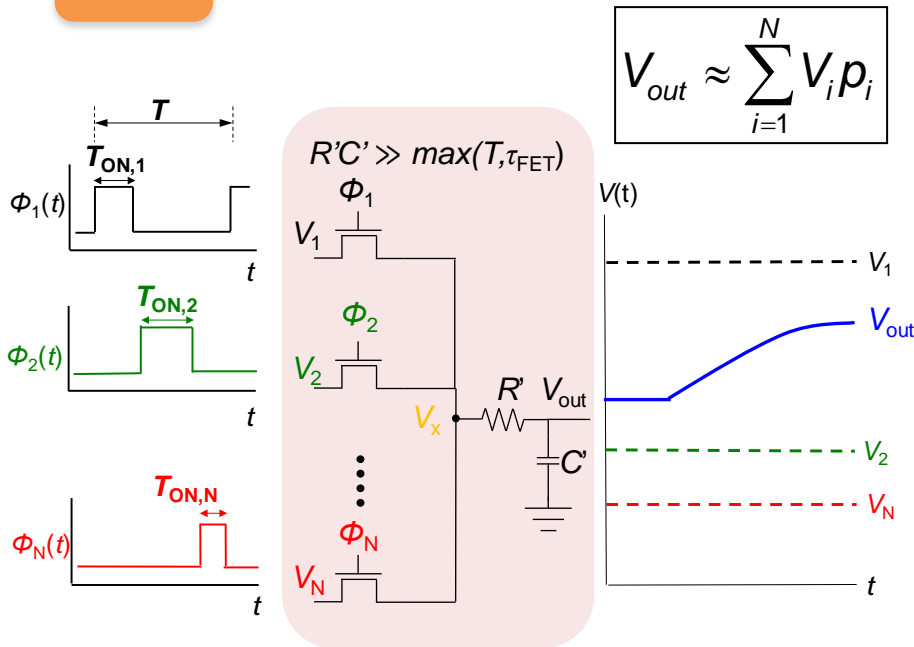
- Low on-off ratio
- Poor current saturation





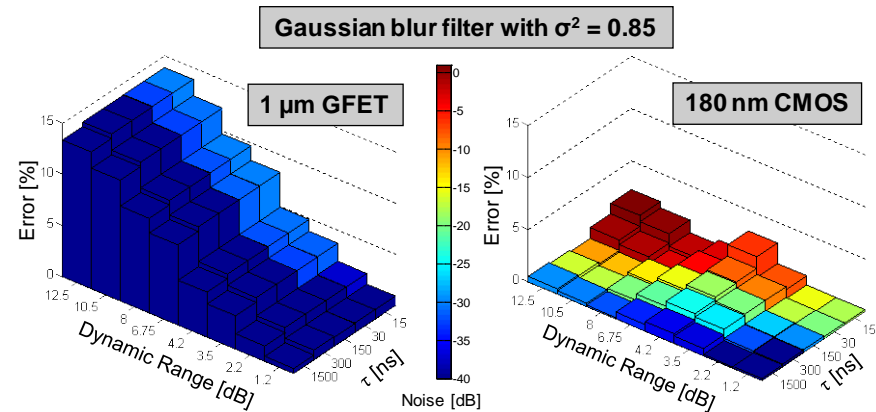
- **Dot product** nanofunction used for image processing, neural networks...
- Takes advantage of native graphene properties (**high μ** , flexible...)
- Tolerates graphene drawbacks (low I_{ON}/I_{OFF} ratio)

Idea:



weights encoded by pulse widths $p_i T$

Simulation with MIT-VS



- + Fast
- + Smaller area
- + Low noise
- Narrow input range (due to low I_{ON}/I_{OFF})

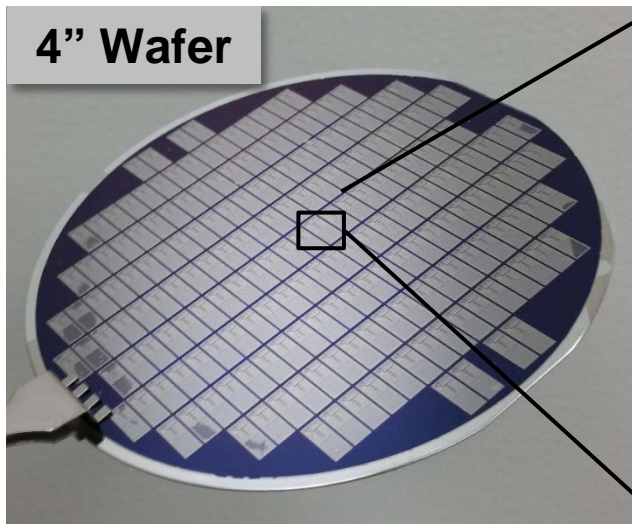
- + High accuracy
- + Wide input range
- Slow and noisy
- Larger area



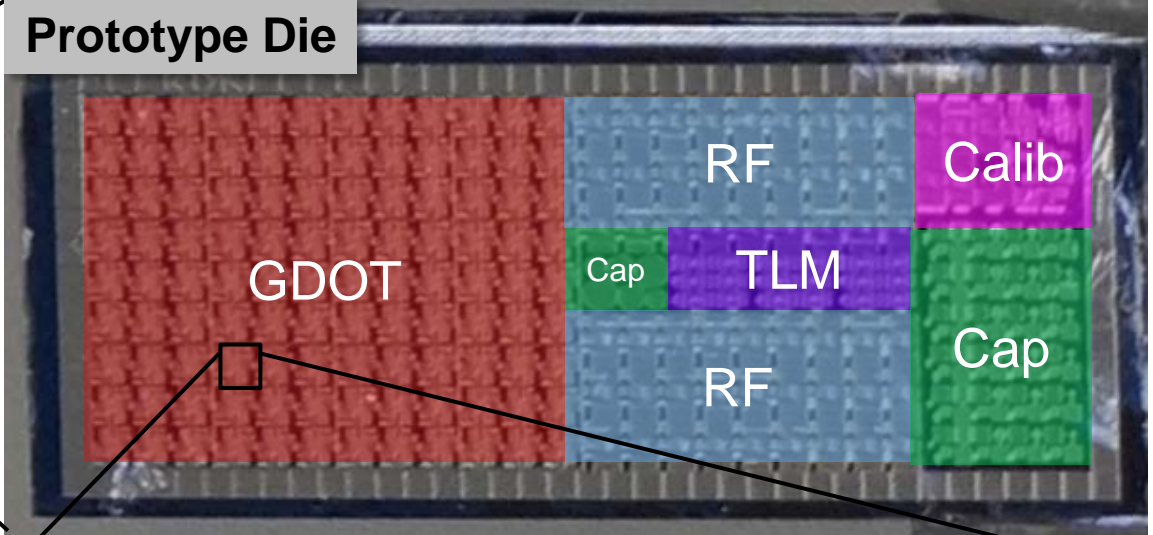
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GDOT Implementation

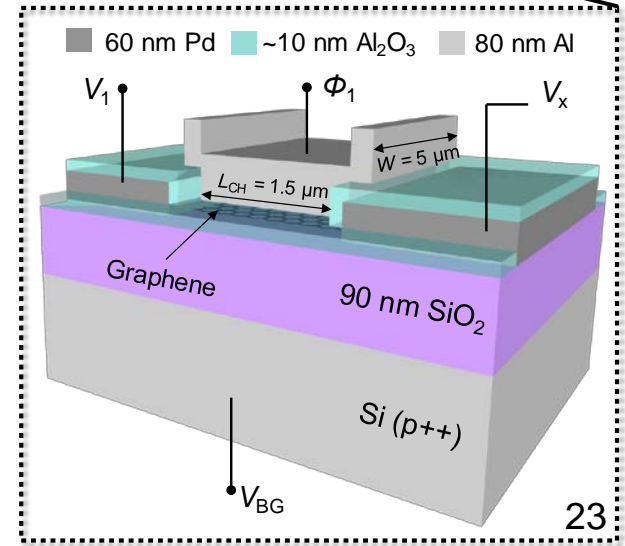
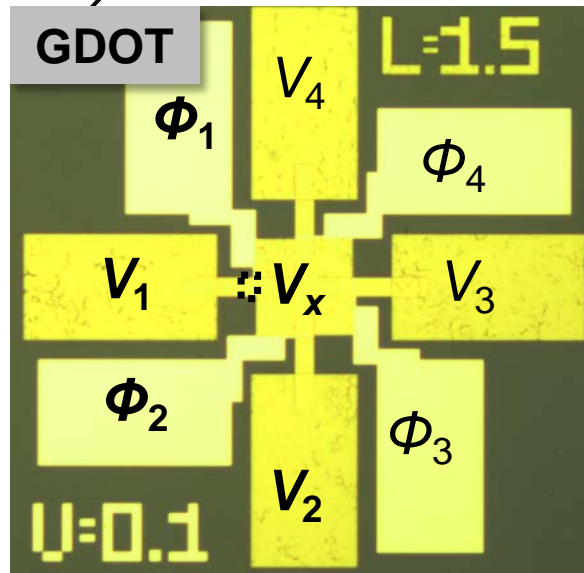


4" Wafer



Prototype Die

- Wafer-scale graphene growth
- Advances in heterogeneous integration
- “Average” devices but unique function



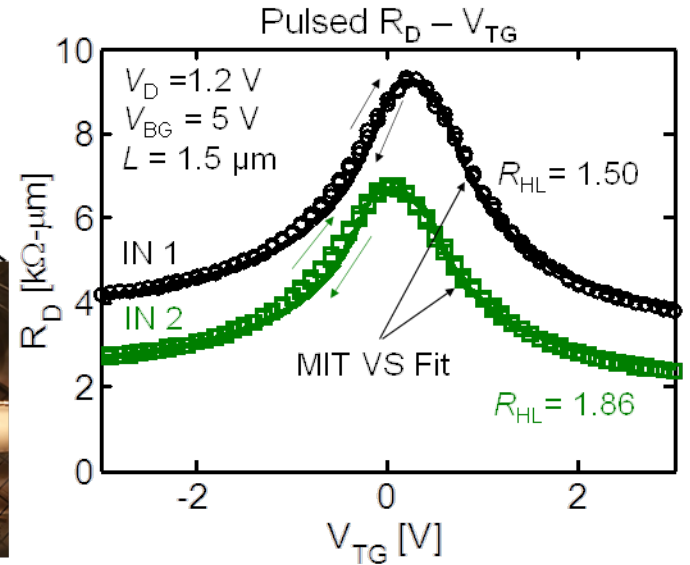
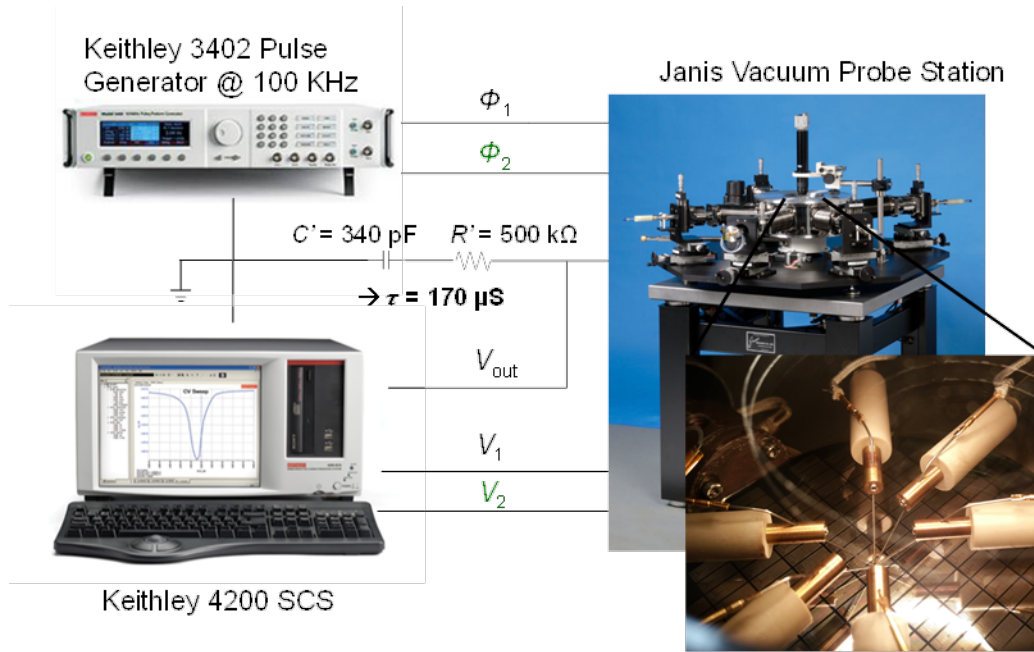


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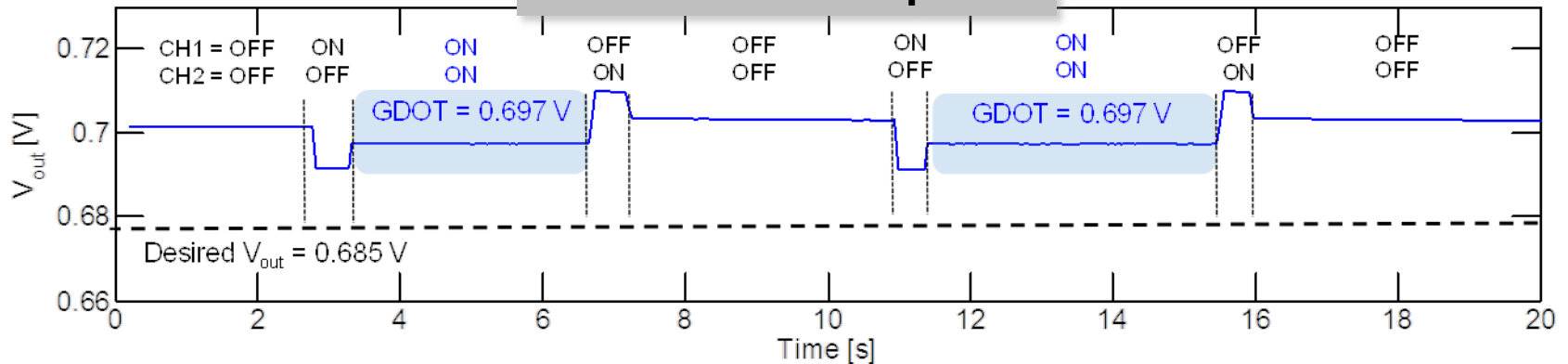
GDOT Prototype

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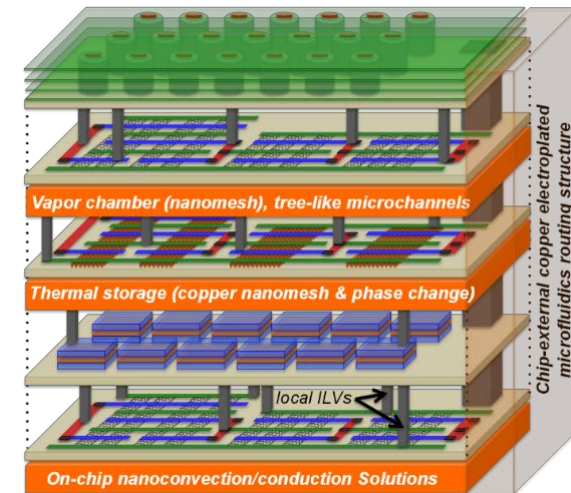
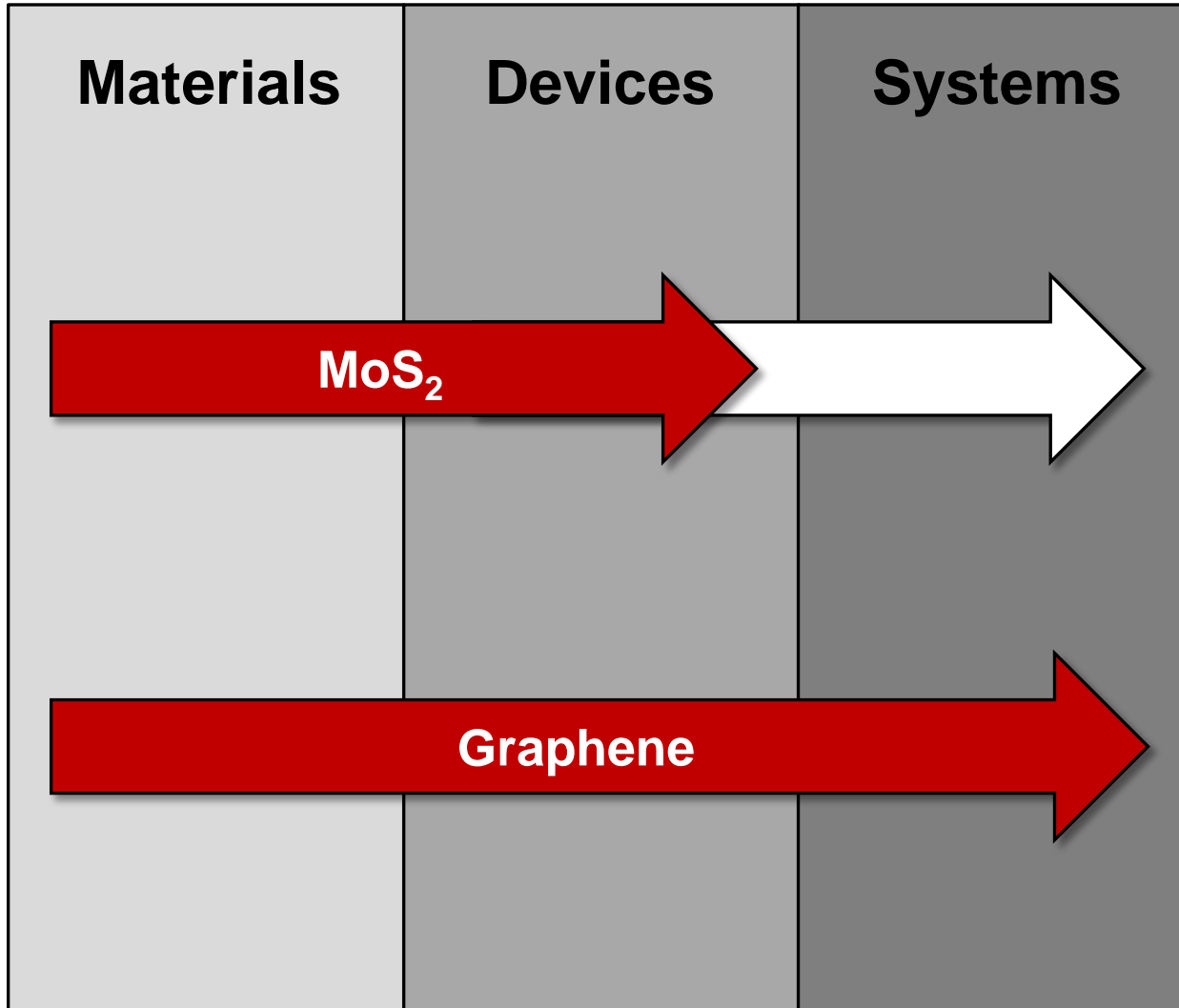
N. Wang, S. Gonugondla, I. Nahlus, N. Shanbhag, E. Pop, *VLSI Symp.* (2016)



2-in GDOT Output



2D Materials to Systems (Today)



M. Aly et al., "Energy-Efficient Abundant-Data Computing: The N3XT 1,000X," *IEEE Computer* 48, 24 (2015)



- Developed S2DS containing accurate models for
 - Carrier transport (v_{sat} , μ , C_q) and contacts
 - Thermal resistance
 - Non-idealities including traps, doping etc.
 - Analytical model of all possible fringe capacitances in a 2D FET
- Used compact models to identify the technology challenges
- Used compact models to design and optimize nanofunctions
- Showcased capability to design and fabricate large-scale systems from 2D materials (graphene and MoS₂)

Thank You!



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